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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	09/512,942
		Filing Date	February 25, 2000
		First Named Inventor	Theodore H. Fedynyshyn
		Art Unit	1752
		Examiner Name	Chu
		Attorney Docket Number	101328-0148
Sheet	1	of	1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
JSC		3148983-B1	09-15-1964	Endermann, et al.	
		3869292-B1	03-04-1975	Peters	
		4115128-B1	09-19-1978	Kita, N.	
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		4377631-B1	03-22-1983	Toukhy, et al.	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
JSC		JP-A 05015772-A1	01-26-1993		
		JP-A 63077952-A1	04-08-1988	Ito, M.	

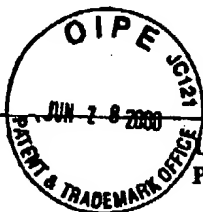
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
JSC		Baidina, I., Podberezskaya, N., Borisov, S., Alekseev, V., Martynova, I., and Kanev, A. Zh. Strukt. Khim. 21, 125 (1980).	
		Clegg, W., Sheldrick, G., and Vater, N. Acta Crystallogr. 38B, 3162 (1980).	
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		Mertesdor, C., et al. Microelectronics Technology, 1995. Pp. 35-55.	
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Examiner Signature	<i>J. Ch</i>	Date Considered	12/2001
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Form PTO-1449
(Rev. 8-83)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO:
101328-148APPLICATION NO:
09/512,942

INFORMATION DISCLOSURE CITATION

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APPLICANT:
Theodore H. FedynshynFILING DATE:
February 25, 2000GROUP ART UNIT:
2852

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE*
JS	AA	3	8	0	1	3	2	7	04/74	Moreau	96	115R	
JS	AB	4	2	0	2	6	9	7	05/80	Van Goethem et al.	430	306	

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		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
JS	BA	1	0	2	0	4	3	8	01/89	Japan			abst	
JS	BB	0	3	2	4	2	7	9	03/91	Japan				X

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

JS	CA	✓	Bruschi, P. et al., "Gas Sensing with Conducting Polymer Thin Film Resistors Obtained From Commercial Photoresist Patterns," <i>Sens. Microsyst., Proc. Ital. Conf.</i> , Di Natale et al. (Editors), 69-73 (1996);										
	CB	✓	Crivello, J. and Mao, Z., "Preparation and Cationic Photopolymerization of Organic-Inorganic Hybrid Matrixes," <i>Chem. Mater.</i> , vol. 9, 1562-69 (1997);										
	CC	✓	Dagani, R., "Putting the 'Nano' into Composites," <i>Chemical</i> , 25-37 (June 7, 1999);										
	CD	✓	Dumpich, G. et al., "Direct Writing of Metallic Nanostructures by Means of Metal Colloids," <i>Materials Science Forum</i> , vols. 287-8, 413-6 (1998);										
	CE	✓	Kaplan, L.H. and Zimmerman, S.M., "Enhanced E-Beam Sensitivity of Resist," <i>IBM Technical Disclosure Bulletin</i> , vol. 21, no. 7, p. 2823 (December 1978);										
	CF		Mucha, et al., "Plasma Etching of Materials Used in Microelectronic Manufacturing," <i>Introduction to Microlithography</i> , L. Thompson et al., (editors), 449-64 (1994);										
	CG	✓	Pu, Jia-Ling et al., "Photobinding of Colloidal Particles by Means of Surface Modification," <i>Journal of Imaging Science</i> , vol.32, no. 3, 129-34 (May/June 1988);										
	CH	✓	Pu, Jia-Ling et al., "Photobinding of Colloidal Particles by Means of Surface Modification. II. Surface Azido Density and Dispersibility," <i>Journal of Imaging Science</i> , vol.32, no.6, 232-7 (November/December 1988);										
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EXAMINER INITIAL		DOCUMENT NUMBER								DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE*
JSC	AC	5	6	4	8	1	5	9		07/97	Sato	428	327	
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														YES	NO
JSC	BC	3	2	3	7	1	1	3		10/91	Japan			abst	
JSC	BD	5	2	1	6	2	3	2		08/93	Japan			abst	
JSC	BE	0	8	3	6	2	6	5		02/96	Japan				X

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OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

JSC	CI	✓	Pu, J.-L. et al., "Photobinding of Colloidal Particles by Means of Surface Modification. III. Influences of Dispersibility and Photoactivity of Azido Groups on the Colloidal Surface," <i>Journal of Imaging Science</i> , vol. 33, no. 1, 33-35 (January/February 1989);											
	CI	✓	Vossmeier, T. et al., "Light-Directed Assembly of Nanoparticles," <i>Angew. Chem. Int. Ed. Engl.</i> , vol. 36, no. 10, 1080-3 (1997);											
	CK	✓	Zambounis, J.S. et al., "Latent Pigments Activated by Heat," <i>Nature</i> , vol. 388, 131-2 (July 10, 1997).											
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